



April 15, 2009
OS DESIGN DEPT.2

SUT10 series EMI/EMS Test results

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No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	O.k.
2	Radiated emission	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	O.k.
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Contact discharge voltage 8[kV] (EN61000-4-2 Level 4) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.k.
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4)Testing field strength 10[V/m] (EN61000-4-3 Level 3) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.k.
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	O.k.
6	Surge immunity test (EN61000-4-5)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Test voltage Line to line 2[kV] (Level 3) (5) Testing circuitry Fig.3	(1)The power supply is not stop. (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	O.k.

○ Testing circuitry

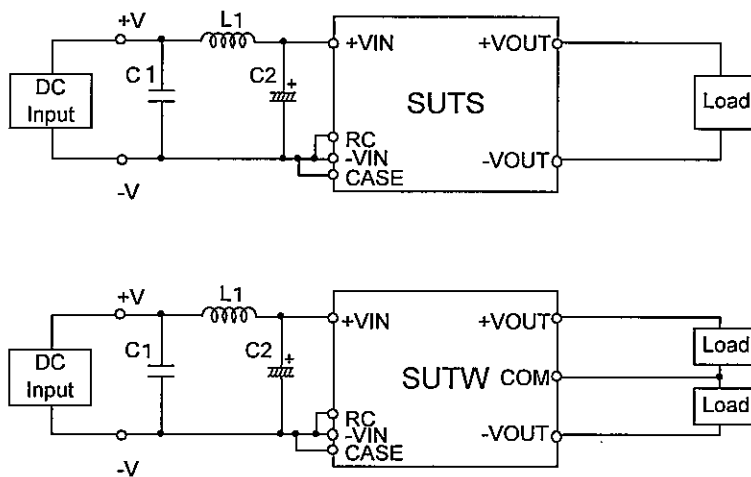


Fig.1 Testing circuitry

SUT□1005

L1 : 0.5 μ H	CI4-0R5	(KORIN ELECTRONICS)
C1 : 25V 22 μ F	GRM32ER71C226K	(MURATA)
C2 : 25V 470 μ F	UPM1E471M	(NICHICON)

SUT□1012

L1 : 1 μ H	CI4-1R0	(KORIN ELECTRONICS)
C1 : 25V 10 μ F	C3225JB1E106M	(TDK)
C2 : 25V 220 μ F	UPW1E221M	(NICHICON)

SUT□1024

L1 : 2.2 μ H	CY3H-2R2	(KORIN ELECTRONICS)
C1 : 50V 3.3 μ F	C3225JB1H335M	(TDK)
C2 : 50V 100 μ F	UPM1H101M	(NICHICON)

SUT□1048

L1 : 10 μ H	CY3H-100	(KORIN ELECTRONICS)
C1 : 100V 2.2 μ F	C4532JB2A225M	(TDK)
C2 : 100V 47 μ F	UPW2A470M	(NICHICON)

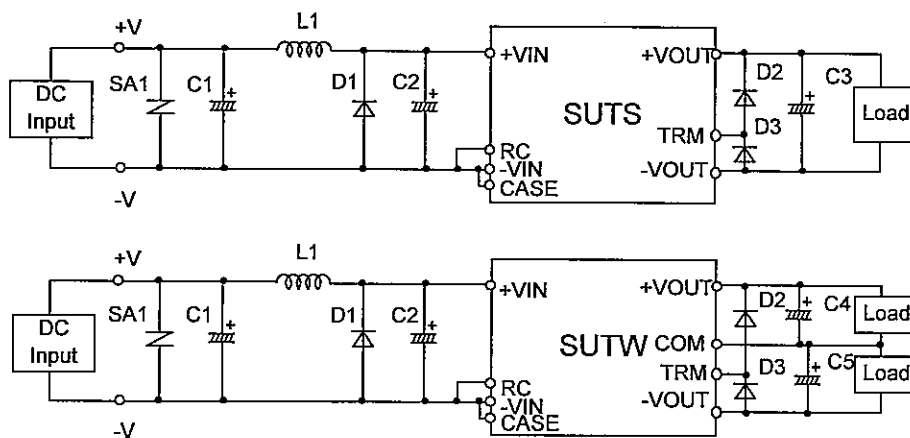


Fig.2 Testing circuitry

SUT□1005

SA1 : 18V	ERZV10D180	(MATSUSHITA ELECTRONIC)
L1 : 0.5μH	C14-0R5	(KORIN ELECTRONICS)
D1 : 200V 3A	ERD32-02	(FUJI ELECTRIC)
C1 : 25V 2700μF	UPW1E272M	(NICHICON)
C2 : 25V 470μF	ELXY250ELL471M	(NIPPON CHEMI-COM)

SUT□1012

SA1 : 27V	ERZV10D270	(MATSUSHITA ELECTRONIC)
L1 : 1μH	C14-1R0	(KORIN ELECTRONICS)
D1 : 200V 3A	ERD32-02	(FUJI ELECTRIC)
C1 : 25V 1500μF	UPW1E152M	(NICHICON)
C2 : 25V 220μF	ELXY250ELL221M	(NIPPON CHEMI-COM)

SUT□1024

SA1 : 47V	ERZV10D470	(MATSUSHITA ELECTRONIC)
L1 : 2.2μH	CY3H-2R2	(KORIN ELECTRONICS)
D1 : 200V 3A	ERD32-02	(FUJI ELECTRIC)
C1 : 50V 100μF	UPM1H101M	(NICHICON)
C2 : 50V 100μF	UPM1H101M	(NICHICON)

SUT□1048

SA1 : 100V	ERZV10D101	(MATSUSHITA ELECTRONIC)
L1 : 10μH	CY3H-100	(KORIN ELECTRONICS)
D1 : 200V 3A	ERD32-02	(FUJI ELECTRIC)
C1 : 100V 47μF	UPW2A470M	(NICHICON)
C2 : 100V 47μF	UPW2A470M	(NICHICON)

SUS/SUCS10□□3R3, SUS/SUCS10□□05

C3 : 25V 470μF	ELXY250ELL221M	(NIPPON CHEMI-COM)
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SUS/SUCS10□□12, SUS/SUCS10□□15

C3 : 50V 100μF	UPM1H101M	(NICHICON)
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SUW/SUCW10□□12, SUW/SUCW10□□15

C4, C5 : 50V 100μF	UPM1H101M	(NICHICON)
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SU□/SUC□10

D2, D3 : 100V 1A	S5566B	(TOSHIBA)
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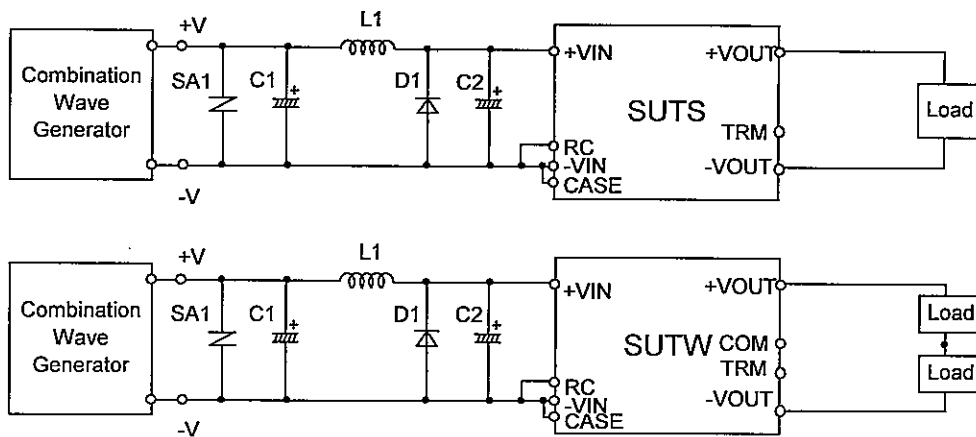


Fig.3 Surge immunity testing circuitry

SUT□1005

SA1 : 18V		ERZV10D180	(MATSUSHITA ELECTRONIC)
L1 : 0.5 μ H		CI4-0R5	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 25V 2700 μ F		UPW1E272M	(NICHICON)
C2 : 25V 470 μ F		ELXY250ELL471M	(NIPPON CHEMI-COM)

SUT□1012

SA1 : 27V		ERZV10D270	(MATSUSHITA ELECTRONIC)
L1 : 1 μ H		CI4-1R0	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 25V 1500 μ F		UPW1E152M	(NICHICON)
C2 : 25V 220 μ F		ELXY250ELL221M	(NIPPON CHEMI-COM)

SUT□1024

SA1 : 47V		ERZV10D470	(MATSUSHITA ELECTRONIC)
L1 : 2.2 μ H		CY3H-2R2	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 50V 100 μ F		UPM1H101M	(NICHICON)
C2 : 50V 100 μ F		UPM1H101M	(NICHICON)

SUT□1048

SA1 : 100V		ERZV10D101	(MATSUSHITA ELECTRONIC)
L1 : 10 μ H		CY3H-100	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 100V 47 μ F		UPW2A470M	(NICHICON)
C2 : 100V 47 μ F		UPW2A470M	(NICHICON)